

BSC205N10LS G-VB Datasheet N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{(BR)DSS} (V)	$r_{DS(on)}(\Omega)$	I _D (A)		
100	0.017 at V _{GS} = 10 V	30		

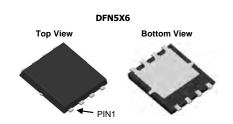
FEATURES

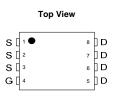
- Trench Power MOSFET
- 175 °C Junction Temperature
- Low Thermal Resistance Package
- 100 % R_g Tested

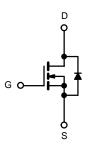


APPLICATIONS

• Isolated DC/DC Converters







N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	is (T _A = 25 °C, u	ınless other	wise noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V_{DS}	100	V	
Gate-source voltage		V_{GS}	± 20	V	
Continuous drain current (T _J = 150 °C)	T _C = 25 °C		30		
	T _C = 70 °C	1 .	19		
	T _A = 25 °C	l _D	10 ^{b, c}		
	T _A = 70 °C	1	8.5 ^{b, c}	1	
Pulsed drain current (t = 100 µs)		I _{DM}	75	A	
Continuous source-drain diode current	T _C = 25 °C		56		
	T _A = 25 °C	l _S	4.5 b, c		
Single pulse avalanche current	L = 0.1 mH	I _{AS}	20		
Single pulse avalanche energy	L = U. I IIII	E _{AS}	20	mJ	
Maximum power dissipation	T _C = 25 °C		60		
	T _C = 70 °C		40	W	
	T _A = 25 °C	P _D	5 b, c	VV	
	T _A = 70 °C	1	3.2 b, c		
Operating junction and storage temperature range		T _J , T _{stg}	-55 to +150	°C	
Soldering recommendations (peak temperature) ^c			260	7	

THERMAL RESISTANCE RATINGS							
PARAMETER	_	SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum junction-to-ambient ^b	t ≤ 10 s	R _{thJA}	20	25	°C/W		
Maximum junction-to-case (drain)	Steady state	R _{th IC}	1.6	2	C/W		

- No e a. Package limited
- b. Surface mounted on 1" x 1" FR4 board
- c. t = 10 s

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PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
S a ic			I.				
Drain-source breakdown voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100	-	-	V	
V _{DS} temperature coefficient	$\Delta V_{DS}/T_{J}$	I _D = 10 mA	-	81	-		
V _{GS(th)} temperature coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-7.5	-	mV/°C	
Gate-source threshold voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	-	5	V	
Gate-source leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	100	nA	
Zero gate voltage drain current		V _{DS} = 100 V, V _{GS} = 0 V	-	-	1	μΑ	
	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 70 °C	-	-	15		
On-state drain current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	40	-	-	Α	
Drain-source on-state resistance ^a	D	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	0.0170	-	Ω	
	R _{DS(on)}	$V_{GS} = 7.5 \text{ V}, I_D = 10 \text{ A}$	-	0.0200	-		
Forward transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A	-	46	-	S	
D namic ^b							
Input capacitance	C _{iss}		-	1470	-	pF	
Output capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	132	-		
Reverse transfer capacitance	C _{rss}		-	11.2	-		
Total gate charge	0	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	20	-	nC	
Total gate charge	Q_g	V _{DS} = 50 V, V _{GS} = 7.5 V, I _D = 10 A	-	15	-		
Gate-source charge	Q _{gs}		-	6.45	-		
Gate-drain charge	Q _{gd}		-	3.5	-		
Output charge	Q _{oss}	V _{DS} = 50 V, V _{GS} = 0 V	-	22	-	Ī	
Gate resistance	R _g	f = 1 MHz	0.2	0.76	1.4	Ω	
Turn-on delay time	t _{d(on)}		-	12	24		
Rise time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_L = 5 \Omega, \text{ I}_D \cong 10 \text{ A},$	-	5	10	1	
Turn-off delay time	t _{d(off)}	V_{GEN} = 10 V, R_g = 1 Ω	-	19	38	Ī	
Fall time	t _f		-	5	10]	
Turn-on delay time	t _{d(on)}		-	15	30	ns	
Rise time	t _r	V_{DD} = 50 V, R_L = 5 Ω , I_D \cong 10 A,	-	6	12		
Turn-off delay time	t _{d(off)}	V_{GEN} = 7.5 V, R_g = 1 Ω	-	19	38		
Fall time	t _f		-	5	10	1	
D ain-So ce Bod Diode Cha ac e i	ic						
Continuous source-drain diode current	I _S	T _C = 25 °C	-	-	56.8	А	
Pulse diode forward current	I _{SM}				80] A	
Body diode voltage	V_{SD}	$I_S = 5 A$, $V_{GS} = 0 V$	-	0.78	1.1	V	
Body diode reverse recovery time	t _{rr}		-	43	86	ns	
Body diode reverse recovery charge	Q _{rr}	1 10 A 11/44 100 A/v- T 05 00	-	72	144	nC	
Reverse recovery fall time	t _a	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	-	33	-	ns	
Reverse recovery rise time	t _b		-	10	-		

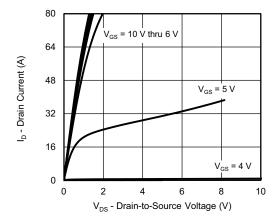
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- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %
- b. Guaranteed by design, not subject to production testing

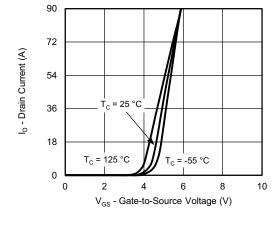
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



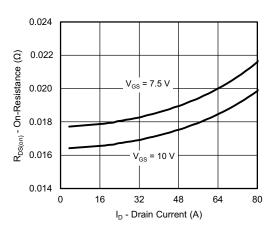
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



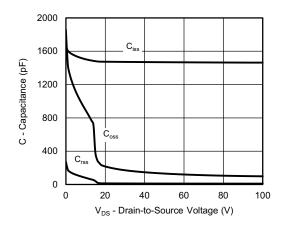
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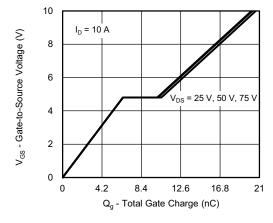
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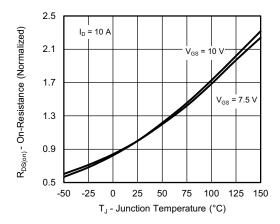
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Ca aci ance



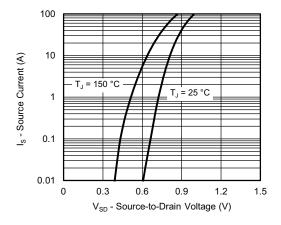
Ga e Cha ge



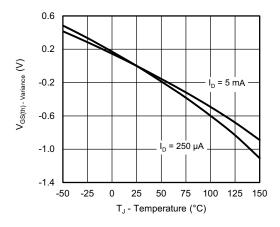
On-Re i ance . J nc ion Tem e a e



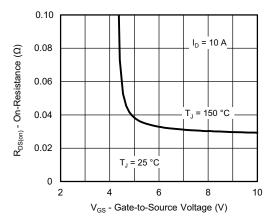
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



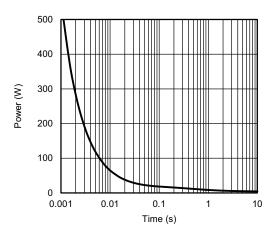
So ce-D ain Diode Fo a d Vol age



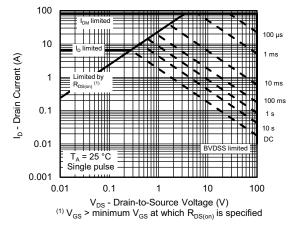
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On-Re i ance . Ga e- o-So ce Vol age



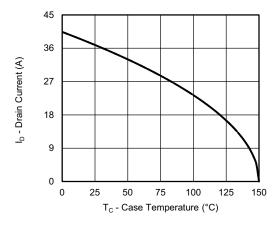
Single P I e Po e , J nc ion- o-Ambien



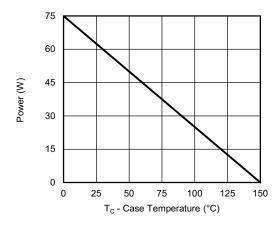
Safe O e a ing A ea, J nc ion- o-Ambien



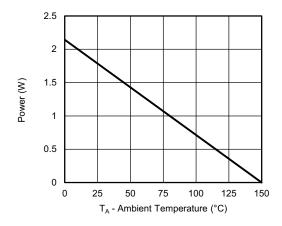
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



C en De a ing a



Po e, J nc ion- o-Ca e



Po e, J nc ion- o-Ambien

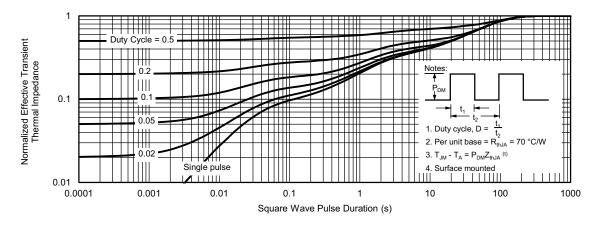
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a. The power dissipation P_D is based on T_J max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit

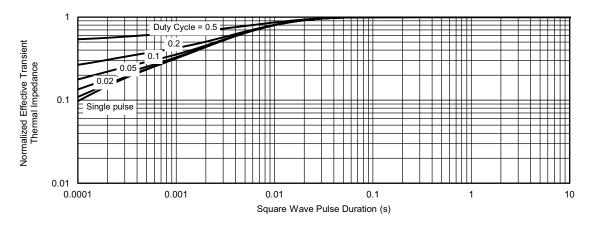
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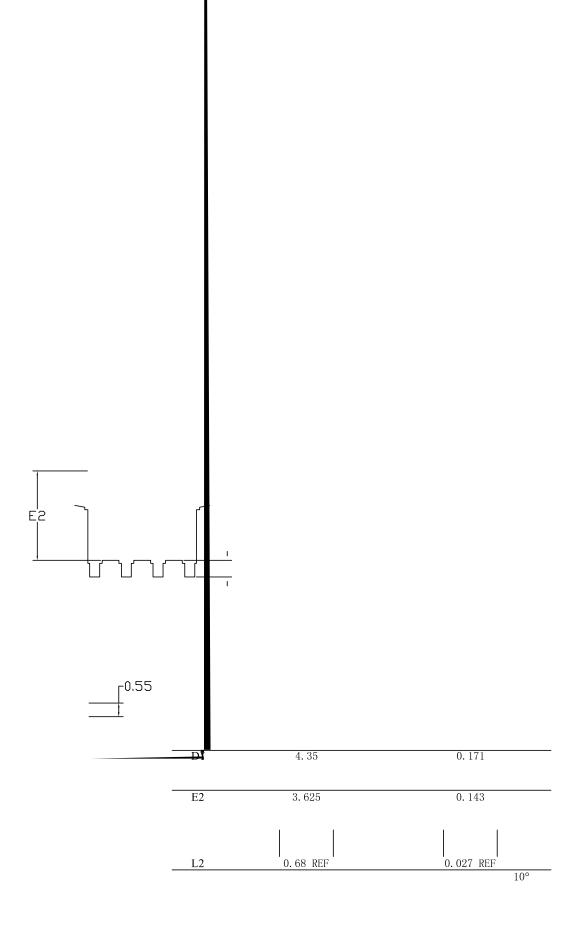
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



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